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(54) SYSTEM AND METHOD FOR PARALLAX-BASED DETERMINATION OF DIMENSION RELATED TO AN OBJECT

SYSTEM UND VERFAHREN ZUR PARALLAXBASIERTEN DIMENSIONSBESTIMMUNG IM BEZUG AUF EIN OBJEKT

SYSTÈME ET MÉTHODE DE DÉTERMINATION BASÉE SUR UN PARALLAXE DE DIMENSION RELATIVE À UN OBJET

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DescriptionTechnical Field

- 5 **[0001]** The present disclosure generally relates to optical systems that can determine one or more dimensions associated with an object in an environment.

Description of the Related Art

- 10 **[0002]** There are many types of optics-based technologies for determining range and/or dimensions of objects in an environment, for instance depth camera technologies, including, for example, time of flight, passive stereo, active stereo, and structured light. Such technologies enable, for instance, a depth camera system to determine depth values for a scene. For example, each depth value may be representative of a distance or range from the depth camera system to a particular object contained within the environment.

- 15 **[0003]** Systems that perform time of flight techniques rapidly pulse a light source and determine a delay between emission of the light and reception of light reflected from various locations in the scene. A system that performs time of flight techniques typically requires a complex, custom imaging sensor.

- [0004]** Passive stereo cameras typically rely on texture (e.g., printing) on a surface of the object being scanned. However, in transport and logistics applications there is no guarantee that an object (e.g., a blank cardboard box) will bear texture. Active stereo cameras (e.g., Microsoft Kinect Version 1), project a light pattern (i.e., structured light) on the surface of the object to be scanned, to ensure the presence of texture.

- [0005]** Systems that employ stereo techniques match corresponding image points respectively seen by plural cameras. Such correspondence detection requires significant processing, particularly when applied to image regions that are homogenous in color or intensity. Thus, in order to perform well with respect to untextured scenes, depth camera systems often augment stereo techniques by using a projected light pattern, also known as active stereo. Rectifying the images can simplify processing by allowing the correlation to occur along a linear shift called the epipolar line. However, stereo techniques still include a significant processing time and cost.

- [0006]** Structured light systems typically include a camera and a projector. The projector projects a pattern of light (i.e., structured light). The system compares the locations of certain features of the pattern in a captured image with locations of the features in a reference image to determine disparities. Such disparities can be used to determine depth at each location. However, for complex patterns, detection of pattern features can be computationally expensive, similar to stereo techniques. Other structured light techniques exist, as well. For example, temporal structured light methods use a sequence of light patterns emitted by a programmable projector to provide accurate range maps. However, temporal techniques typically require the scene to remain stationary.

- 35 **[0007]** There are several products used in transportation and logistics applications, each associated with some set of problems. For example, Datalogic's DM3610 dimensioner implements a scanned laser Time of Flight method. This approach suffers due to various moving parts, high noise on black objects, and large expensive optics. Datalogic's DM3500 dimensioner implements a scanned laser spot triangulation approach. This approach also suffers due to moving parts and large optics. Unlike the DM3610, noise from black objects is less of a problem for the DM3500, however the DM3500 still suffers from noise due to temperature and mechanical sensitivity associated with the parallax angle. The system described in US4929843 by Thomas A. Chmielewski Jr., et al uses a parallax approach, with a single projected laser line and two-dimensional (2D) imager. Other devices employ either a linear or 2D structured light parallax approach. The Chmielewski approach is simple, and does not require moving parts or expensive optics. However, systems such as this can suffer from sensitivity to variations in reflectivity on a surface of the scanned objects, for example due to text or other printing, and/or tape or film on an object (e.g., cardboard box), which can distort the location of the reflected light pattern. The Chmielewski system can suffer from sensitivity to small changes in the parallax angle caused by temperature changes or vibration. Most parallax approaches further suffer from issues with shadowing.

- 45 **[0008]** The object may bear indicia (e.g., human and/or machine-readable symbols, markings or images). Such indicia vary the reflectance of the object, and thus interfere with the ability of conventional dimensioners to correctly or accurately determine dimensions of an object.

[0009] The above noted techniques generally require a trade-off between lateral resolution, range resolution, motion tolerance, processing cost, and/or hardware complexity to achieve their respective results.

[0010] Various implementations of the structures and methods described herein can be used to measure a volume of objects moving on a conveyor belt.

- 55 **[0011]** From the United States patent US 6 028 672 A or the United States patent US 2003/0002051 A1 a system and method for three dimensional imaging according to the precharacterizing part of claim 1 is known. It is an object of the invention to accomplish a system and method capable of reducing errors while at the same time providing a robust and compact solution. This and other objects are achieved by the system according to claim 1 and the method according to

claim 14.

[0012] An optical system implements a dual "differential" parallax approach, reducing or even eliminating error or noise. For example, a linear dimensioner (*i.e.*, not 2D) employs a dual "differential" parallax approach. This approach realizes the simplicity and low cost typically associated with a linear parallax-based system (*e.g.*, the Chmielewski system), with the robustness typically associated with an active stereo-based system, to minimize errors caused by varying reflectance (*i.e.*, object texture) across a surface of objects to be scanned, and errors due to vibration of the laser relative to the receiving optics (*i.e.*, parallax angle error). The approach described herein may also advantageously mitigate the effects of up and downstream shadowing. Thus, the approach described herein advantageously reduces errors experienced by a single laser parallax camera.

BRIEF DESCRIPTION OF THE SEVERAL VIEWS OF THE DRAWINGS

[0013] The patent or application file contains at least one drawing executed in color. Copies of this patent or patent application publication with color drawing(s) will be provided by the Office upon request and payment of the necessary fee.

[0014] In the drawings, identical reference numbers identify similar elements or acts. The sizes and relative positions of elements in the drawings are not necessarily drawn to scale. For example, the shapes of various elements and angles are not necessarily drawn to scale, and some of these elements may be arbitrarily enlarged and positioned to improve drawing legibility. Further, the particular shapes of the elements as drawn, are not necessarily intended to convey any information regarding the actual shape of the particular elements, and may have been solely selected for ease of recognition in the drawings.

Figure 1 is a schematic diagram of an environment that includes a conveyor, an object transported by the conveyor, and a system that employs a light source to produce a structured light pattern, a light sensor, a pair of angled reflectors that produce dual "differential" parallax images of the structured light pattern on the object, and which determines at least one dimension (*e.g.*, range, height, width) associated with the object, according to at least one illustrated implementation.

Figure 2 is a schematic diagram illustrating a relative positioning and orientation of a pair of angled reflectors and an image sensor of the system of Figure 1 showing representative ray traces, according to at least one illustrated implementation.

Figure 3 is an image of laser scan lines returned from an object at three respective distances or ranges, according to at least one illustrated embodiment, with the light bandpass filter removed and exposure time increased to facilitate human viewing.

Figure 4 is an isometric view of a calibration template which can be used to calibrate the system of Figure 1, according to at least one illustrated implementation.

Figure 5 is an image of instances of a structured light pattern (*e.g.*, laser scan lines) returned from the calibration template of Figure 4, according to at least one illustrated implementation.

Figure 6 is a graph of a calibration image after locating a center of a structured light pattern (*e.g.*, laser line), according to at least one illustrated implementation, a curvature caused by lens distortion.

Figure 7 is a graph of range calibrated at five distances, according to at least one illustrated implementation.

Figure 8 is an image of two instances of a structured light pattern (*e.g.*, laser line) captured by the light sensor of Figure 1 after being returned from an object and reflection by the two angled reflectors, according to at least one illustrated implementation.

Figure 9 is a graph showing a result of finding the centroid of the two instances of the structured light pattern (*e.g.*, laser lines) of Figure 8 detected by the light sensor, according to at least one illustrated implementation.

Figure 10 is a graph of calibrated results from analysis of the result of finding the centroid of the two instances of the structured light pattern (*e.g.*, laser lines) of Figure 8, according to at least one illustrated implementation.

Figure 11 is a graph of results from analysis of the result of finding the center of the two instances of the structured light pattern (*e.g.*, laser lines) of Figure 8, according to at least one illustrated implementation.

Figure 12 is a graph that demonstrates that the "differential" approach taught herein advantageously inherently cause errors to cancel out, according to at least one illustrated implementation.

Figure 13 is a flow diagram showing a method of operating a system to determine at least one dimension (*e.g.*, range, height, width, length) associated with an object, according to at least one illustrated implementation.

DETAILED DESCRIPTION

[0015] In the following description, certain specific details are set forth in order to provide a thorough understanding of various disclosed embodiments. However, one skilled in the relevant art will recognize that embodiments may be practiced without one or more of these specific details, or with other methods, components, materials, etc. In other

instances, well-known structures have not been shown or described in detail to avoid unnecessarily obscuring descriptions of the embodiments.

[0016] Unless the context requires otherwise, throughout the specification and claims that follow, the word "comprising" is synonymous with "including," and is inclusive or open-ended (*i.e.*, does not exclude additional, unrecited elements or method acts).

[0017] Reference throughout this specification to "one embodiment" or "an embodiment" means that a particular feature, structure or characteristic described in connection with the embodiment is included in at least one embodiment. Thus, the appearances of the phrases "in one embodiment" or "in an embodiment" in various places throughout this specification are not necessarily all referring to the same embodiment. Furthermore, the particular features, structures, or characteristics may be combined in any suitable manner in one or more embodiments.

[0018] As used in this specification and the appended claims, the singular forms "a," "an," and "the" include plural referents unless the context clearly dictates otherwise. It should also be noted that the term "or" is generally employed in its broadest sense, that is, as meaning "and/or" unless the context clearly dictates otherwise.

[0019] The headings and Abstract of the Disclosure provided herein are for convenience only and do not interpret the scope or meaning of the embodiments.

[0020] Figure 1 shows an environment 100 that includes a conveyor 102, an object 104 transported by the conveyor 102, and a system 106 that employs a light source (*e.g.*, laser, LEDs) 108, a light sensor 110, and a pair of angled reflective portions or reflectors 112a, 112b that produce dual "differential" parallax images of a structured light pattern (*e.g.*, laser line, scan line, line of dots or spots, multiple lines) 114 projected on a surface 116 of the object 104 which are detected by the light sensor 110, and processor-based circuitry (*i.e.*, processor subsystem) 118 which determines at least one dimension (*e.g.*, range R, height H, width W, length L) associated with the object 104, according to at least one illustrated embodiment.

[0021] The environment 100 can take the form of any of a variety of spaces. A coordinate system 120 with X-axis, Y-axis and Z-axis is illustrated to facilitate description of the operation of the system 106 in the environment 100.

[0022] The conveyor 102 can take any of a variety of forms, including for example, a conveyor belt 102a or roller conveyor, etc. The conveyor 102 includes a suitable motor (*e.g.*, electric motor) 102b coupled to drive the conveyor belt 102a, and hence objects 104 carried by the conveyor 102, past a field of view (represented by broken line box 122) of the light sensor. As illustrated by arrow 124, the conveyor 102 transports the object 104 in a direction along the X-axis with respect to the field of view 122. In some implementations, the conveyor 102 can operate at a relatively high speed, for example approximately 3.5 meters/second. A top surface 102c of the conveyor 102 may be positioned at a fixed and/or known distance from the pair of angled reflective portions or reflectors 112a, 112b. A conveyor 102 is useful for high speed processing, although a conveyor is not essential, and in some implementations the object 104 may be positioned on a stationary surface. The conveyor 102 typically includes a sensor to detect position and/or speed which is communicatively coupled (arrow 105) to provide information representative of position and/or speed to the processor-based circuitry 118. For example, the conveyor can include an encoder, tachometer, or other belt speed measurement device 103. Information (*e.g.*, the position of the conveyor each time an image is taken and processed, speed) generated from the sensor 103 is used by the processor-based circuitry 118 to determine the dimensions of the object along the direction of travel 124 of the conveyor 102 (*e.g.*, used to determine length of the object 104).

[0023] The object 104 can take any of a large variety of forms. Typically, the object 104 will take the form of a parcel, box, can, or other packaging, although is not limited to such. The object 104 may be characterized by a set of dimensions, for example a height H along the Z-axis, a width W along the Y-axis, and a length L along the X-axis. While illustrated as aligned, width and/or length are not necessarily aligned with the X-axis and Y-axis. For example, a long skinny package may be rotated at, for example, 45 degrees to a length of a conveyor belt. Where the top surface 102c of the conveyor 102 is positioned at a fixed and/or known distance from the pair of angled reflective portions or reflectors 112a, 112b, the height H of the object 104 can be determined as the difference of a distance of the top surface 102c of the conveyor 102 from the pair of angled reflective portions or reflectors 112a, 112b and the range (*i.e.*, distance of the surface 116 of the object 104 from the pair of angled reflective portions or reflectors 112a, 112b).

[0024] The object 104 may bear indicia (*e.g.*, human and/or machine-readable symbols, markings or images) 126. Such indicia 126 typically interfere with the ability of conventional dimensioners to correctly or accurately determine dimensions of an object 104.

[0025] The light source 108 can take any of a variety of forms operable to produce a structured light pattern (*e.g.*, laser line, scan line, line of dots or spots, multiple lines). For example the light source can take the form of a laser 108 (*e.g.*, laser diode) operable to produce a coherent beam of laser light (*i.e.*, laser beam) 108a. Alternatively, one or more light emitting diodes (LEDs) may emit one or more light beams. The light source 108 (*e.g.*, laser, LEDs) can emit a light beam (*e.g.*, laser spot) toward one or more refractive optics (*e.g.*, Powell lens or cylindrical lens) or diffractive optics (*e.g.*, diffractive lens) to create the structured light pattern 114. Alternatively, one or more mirrors 128 (*e.g.*, flat mirrors, polygonal mirrors) or other optics are positioned to reflect the light beam 108a, and are driven to rotate or pivot as indicated by arrow 130 to rotate or pivot the light beam 108a as indicated by arrow 132 to produce the structured light

pattern (e.g., laser line, scan line) 114 which impinges on the surface 116 (e.g., top) of the object 104 when the object 104 is in the field of view 122 of the light sensor 110.

[0026] The light sensor 110 may take a variety of forms, but advantageously takes the form of a single two-dimensional (2D) image sensor positioned and oriented to concurrently detect reflections from both a first reflective portion 112a and a second reflective portion 112b, which are angled with respect to one another to create a parallax image on the linear image sensor 110. One or more lenses 111 (one shown) are typically arranged along an input optical axis to focus the returning light on the image sensor 110. Additionally or alternatively, one or more bandpass filters 113 (one shown) may optionally be employed along the input optical axis. The bandpass filter 113 passes light of the same wavelength (color) as the outgoing light and suppresses other wavelengths of light, to facilitate identification of the structured light pattern in a captured image. Where the conveyor 102 operates at a relatively high speed, for example 3.5 meters/second, the light sensor 110 should have a relative high frame rate, for example approximately 500 to approximately 1000 frames/second.

[0027] The processor-based circuitry 118 may take any of a large variety of forms, typically including one or more processors, for example one or more microprocessors (CPUs) 134, microcontrollers, graphical processing units (GPUs) 136, digital signal processors (DSPs) 138, application-specific integrated circuits (ASICs), programmable gate arrays (PGAs), programmable logic controllers (PLCs), and/or other integrated and/or discrete logic hardware. The processor-based circuitry 118 may include one or more nontransitory computer- or processor-readable media, for example, one or more non-volatile memories, for instance read-only memory (ROM) 140, electronically erasable programmable ROM (EEPROM), flash memory 142, and/or one or more volatile memories, for instance random access memory (RAM) 144. The processor-based circuitry 118 may optionally include one or more image buffers 146, coupled to buffer images captured by the light sensor 110 for processing. While not specifically illustrated, the processor-based circuitry 118 may include one or more spinning media drives and storage, for example a magnetic hard disk drive (HDD) and/or optical disk drive (CD-ROM). The various components of the processor-based circuitry 118 may be communicatively coupled via one or more communications channels or buses 148, for example a power bus, a communications bus, and instructions bus, etc.

[0028] As explained herein, the processor-based circuitry 118 may determine one or more dimensions associated with the object 104 from the dual "differential" parallax images of a laser line 114 on the object 104 as detected by the light sensor 110. Those dimensions can include any one or more of: distance or range R to the object 104 measured along the Z-axis, height H of the object 104 measured for example along the Z-axis, width W of the object measured for example along the Y-axis, and/or length L of the object 104 measured for example along the X-axis. The processor-based circuitry 118 may advantageously accurately determine the dimension(s) even if the object 104 bears printing, indicia, or anything else that would create inconsistency in reflectance over the surface 116 of the object 104.

[0029] Figure 2 shows a relative positioning and orientation of the pair of angled reflective portions or reflectors 112a, 112b, light source 108, and image sensor 110 of the system of Figure 1, including representative ray traces, according to at least one illustrated embodiment. In Figure 2, the X-axis extends horizontally across the plane of the drawing sheet, the Y-axis extends into the plane of the drawing sheet, and the Z-axis extends vertically across the plane of the drawing sheet.

[0030] As illustrated, the first angled reflective portion or reflector 112a and the second reflective portion or reflector 112b are positioned and angled to reflect light to the image sensor 110 from an external environment. For example, the second reflective portion or reflector 112b may be oriented at an acute angle with respect to a principal optical axis (e.g., perpendicular to a light sensitive surface) of the light sensor 110, for instance an included angle of approximately 47 degrees. The first angled reflective portion or reflector 112a and the second reflective portion or reflector 112b are angled with respect to one another, to advantageously provide a parallax effect. For example, the first and the second reflective portions or reflectors 112a, 112b may have an obtuse included angle therebetween, for instance an included angle of approximately 172 degrees therebetween. The first angled reflective portion or reflector 112a and the second reflective portion or reflector 112b may, for example, each have planar reflective faces. The first angled reflective portion or reflector 112a and the second reflective portion or reflector 112b may be two separate and distinct reflectors. Alternatively, the first angled reflective portion or reflector 112a and the second reflective portion or reflector 112b may be portions of a single, integral single-piece construction reflector or mirror. The first angled reflective portion or reflector 112a and the second reflective portion or reflector 112b may include a gap 250 therebetween. The light source 108 may be positioned and oriented to transmit the light beam 108a through the gap 250, either via one or more mirrors or other optics, or directly without the aid of mirrors or optics.

[0031] As illustrated in Figure 2, the laser 108 generates a structured light pattern (e.g., laser scan line or plane) indicated by 208c. As indicated by rays 252a, 252b, the first angled reflective portion or reflector 112a directs light from a first region of interest ROI_1 to the light sensor 110. As indicated by rays 254a, 254b, the second angled reflective portion or reflector 112b directs light from a second region of interest ROI_2 to the light sensor 110. Rays 222a, 222b indicate an extent of the field of view 122 (Figure 1) of the light sensor 110 provided via the first and the second angled reflective portions or reflectors 112a, 112b. Rays 208a and 208b are the extents of the field of view of the image sensor

110 for each mirror, which are the opposite field of view extent of rays 222a and 222b.

[0032] Exemplary principal values for the system illustrated in Figures 1 and 2 are set out in Table 1, below.

Table 1

Design Feature	Value
Mirror Kink Angle	8 degrees
Sensor	5MP CMOS
Lens	25 mm F/8
Mirror Dimensions	150 mm wide x 75 mm tall
Laser Line Angle	Perpendicular to Belt
Mounting Height	1500 mm (kink to belt)
Camera to Mirror Kink	350 mm
ROI Height	200 Rows per ROI
Approximate ROI Row Location	180 - 380, 1676 - 1876
Single Ended Parallax Angle	1.45 - 3.05 degrees
Differential Parallax Angle	2.90 - 6.10 degrees
Max Box Height	930 mm

[0033] Figure 3 is an image 300 of three pairs of structure light patterns as lines 314a, 314b; 314c, 314d; 314e, 314f (collectively 314) of light, returned from an object at three respective distances or ranges R, according to at least one illustrated embodiment. The lines 314 were captured with a light bandpass filter (e.g., red filter) removed and exposure time increased to facilitate human perception of the lines.

[0034] Notably, a first pair of lines 314a, 314b are produced by reflection from the first and the second angled reflective portions or reflectors 112a, 112b, respectively, and are spaced relatively close together as compared to a second pair of lines 314c, 314d. Likewise, the second pair of lines 314c, 314d are produced by reflection from the first and the second angled reflective portions or reflectors 112a, 112b, respectively, and are spaced relatively close together as compared to a third pair of lines 314e, 314f. Likewise, the third pair of lines 314e, 314f are produced by reflection from the first and the second angled reflective portions or reflectors 112a, 112b, respectively. The spacing between the lines 314 in each pair is indicative of a range R of the object from the system (e.g., distance between a portion or surface of the object and the gap 250 (Figure 2) between the first and the second angled reflective portions or reflectors 112a, 112b). The processor-based circuitry 118 may, for example, identify a single point or set of points in a three-dimensional (3D) point cloud.

[0035] Figure 4 is an isometric view of a calibration template 400 which can be used to calibrate the system of Figure 1 at each of a plurality of ranges or distances, according to at least one illustrated embodiment.

[0036] The calibration template 400 may, for example, include an elongated line 402 that extends in first direction (e.g., horizontally in Figure 4), with a plurality of shorter lines 404a, 404b, ... 404n (only three called out, collectively 404) that extend laterally (e.g., vertically in Figure 4) from the elongated line 402 at a defined spacing. The calibration template 400 may optionally include a scale (e.g., set of demarcations with respective values spaced at defined intervals) 406 that extend along the elongated line 402.

[0037] Figure 5 is a calibration image 500 of structured light patterns in the form of lines 552, 554 of light returned from the calibration template 400 of Figure 4, according to at least one illustrated embodiment.

[0038] As visible in Figure 5, each of the lines 552, 554 includes a number of gaps (e.g., black vertical bar or stripe) 502a, 502b (only two called out) which results from the light (e.g., laser) beam passing across of the shorter lines 404 (Figure 4) of the calibration target. The centers of these gaps 502a, 502b are determined to calibrate for the width W of an object (i.e., dimension along a Y-axis).

[0039] Figure 6 is a graph 600 of the calibration image 500 (Figure 5) after locating a center of the lines 552, 554, according to at least one illustrated embodiment.

[0040] The graph 600 includes first and second plots 652, 654, corresponding to lines 552, 554, respectively, of the calibration image 500. In particular, an intensity of each of the lines 552, 554 is plotted for various positions (e.g., pixels) along a horizontal axis of the graph 600. A curvature in the plots 652, 654 is caused by lens distortion and is not otherwise indicative of a dimension (e.g., range R, width W) related to an object (e.g., calibration template 400).

[0041] The system is calibrated for "Y" and "Z" by finding a centroid of each of lines 552, 554 (e.g., laser line) imaged using a target (e.g., calibration template 400 of Figure 4) positioned at known ranges. For this calibration, an overdetermined system of equations was solved using a least squares (MATLAB "\") approach, to generate the calibration factors for dimensions along both the Z-axis and the Y-axis. A third order system was found to give reasonable results.

[0042] Figure 7 is a graph 700 of range R calibrations at five distances or ranges R to the calibration template 400, according to at least one illustrated embodiment.

[0043] In particular, the graph 700 shows a first calibration fit 756a at a range of 570 mm, a second calibration fit 756b at a range of 803 mm, a third calibration fit 756c at a range of 1035 mm, a fourth calibration fit 756d at a range of 1268 mm, and a fifth calibration fit 756e at a range of 1500 mm.

[0044] Figure 8 is an image 800 of two instances of a structured light pattern (e.g., laser line) in the form of lines 852, 854 captured by the light sensor 110 of Figure 1, after being returned from an object 104 (Figure 1) and reflection by the two angled reflectors 112a, 112b (Figures 1, 2), according to at least one illustrated embodiment. In this instance, the object 104 is a single wood box with dimensions of 152.2 mm by 457.1 mm by 304.6 mm.

[0045] Figure 9 is a graph 900 showing a result of finding the centroid of the two instances of the structured light pattern in the form of lines 852, 854 of Figure 8 detected by the light sensor 110 (Figure 1), according to at least one illustrated embodiment.

[0046] The graph 900 includes first and second plots 952, 954, corresponding to lines 852, 854, respectively, of the image 800. In particular, an intensity of each of the lines 552, 554 is plotted for various positions (e.g., pixels) along a horizontal axis of the graph 600. A slight curvature in the plots 952, 954 is caused by lens distortion and is not otherwise indicative of a dimension (e.g., range R, width W) related to an object (e.g., calibration template 400).

[0047] Figure 10 is a graph 1000 of calibrated results from two instances of a structure light pattern in the form of lines (e.g., laser lines) 852, 854 (Figure 8), according to at least one illustrated embodiment.

[0048] A set of blue points 1052 and red points 1054 are the calibrated results from a bottom line 852 and a top line 854, respectively. A set of green points 1056 are an average of the blue and red points 1052, 1054. As can be seen from the graph 1000, the results in the range R or height H (along the Z-axis) and the width W (along the Y-axis) are reasonable. The object in this instance is a box with actual dimensions of 152 mm tall and 457 mm wide. The graph 1000 shows some slight offset between blue points and the red points, which may be the result of a change to the parallax angle in between calibration and run-time when the image of the object (e.g., box) was captured. There is also some error at the corners associated with a height of a belt which carried the object and associated with curvature seen in the object. It may be possible to reduce or even eliminate such error via more refined calibration.

[0049] Figure 11 is a graph 1100 of showing a result of finding a centroid of the two instances of a structure light pattern in the form of lines (e.g., laser scan) 1152, 1154 detected by a light sensor (e.g., light sensor 110 of Figure 1) returned from a box which has a significant variation in reflectance across a surface thereof, according to at least one illustrated embodiment.

[0050] An object, for example a box, that has significant variation in reflectance typically results in significant error in finding a laser centroid, and hence results in error in determined dimensions (e.g., range, distance, height, width). The variation in reflectance can be caused by a variety of factors, for example printing (e.g., text, graphics), tape or other film, and/or dirt or debris on the surface being scanned. The magnitude of the problem is proportional to a width of the laser line or stripe. Relatively more narrow laser lines or stripes are of course more immune to this problem, however it is difficult to implement a narrow stripe over a large working range.

[0051] Figure 12 is a graph 1200 of calibrated results from two instances of a structure light pattern in the form of lines (e.g., laser lines) 1152, 1154 (Figure 11), according to at least one illustrated embodiment.

[0052] A set of blue points 1252 and red points 1254 are the calibrated results from a bottom line 1152 and a top line 1154, respectively. A set of green points 1256 are an average of the blue and red points 1252, 1254. As can be seen from the graph 1200, the "differential" approach taught herein advantageously inherently causes errors to cancel out.

[0053] Figure 13 is a flowchart diagram showing a method 1300 of operating a system to determine dimensions associated with an object, according to at least one illustrated embodiment. The method 1300 can be executed by the system generally described herein. The method 1300 can include additional acts, may omit some acts, and/or may perform one or more acts in a different order than the order set out in Figure 13.

[0054] At 1302, the method 1300 starts for example on starting up or powering of a system or device, or in response to a user input or invocation by a calling routine, program, function call or subprogram.

[0055] At 1304, a light source (e.g., laser, LEDs) emits a light beam. The light may be emitted as a structured light pattern or may be reflected or diffracted as a structure light pattern.

[0056] At 1306, a first reflective surface reflects light returned from an object in an environment. At 1308, the second reflective surface, oriented at a non-zero angle with respect to the first reflective surface, concurrently reflects light returned from an object in the environment. At 1310, a light sensor (e.g., a linear image sensor) detects the light reflected from the object in the environment via both the first and the second reflective surfaces in parallax.

[0057] At 1312, a first half of an image captured by the light sensor is processed via circuitry, for example a lower half

of the image containing the image of one instance of the structured light pattern (e.g., laser line) reflected by one of the reflective portions or reflectors.

[0058] At 1314, the circuitry applies a threshold and one or more filters to the first half of the image, for example to clean up and isolate the image of the instance of the structured light pattern (e.g., laser line or stripe) in the first half of the image. For example, the circuitry may apply a brightness threshold and/or a moving average filter or low pass filter to the image data.

[0059] At 1316, each column of pixels is processed, for example successively column by column. Each column extends in a direction in the image that is parallel to the X-axis, and columns are successively encountered along a direction in the image that is parallel with the Y-axis. For the respective column, the circuitry finds the centroid (e.g., peak, center along axis of column or thickness of line) of the structured light pattern (e.g., laser line) at 1318. For the respective column, the circuitry determines a range (z) and width distance across the belt (y) based on centroid location and column at 1320. For example, the circuitry may look up (e.g., in look-up table) the corresponding range R and/or width W or calculate (e.g., solve defined equation(s)) range R and/or width W.

[0060] At 1322, a second half of the image captured by the light sensor is processed via circuitry, for example an upper half of the image containing the image of one instance of the structured light pattern (e.g., laser line) reflected by one of the reflective portions or reflectors.

[0061] At 1324, the circuitry applies a threshold and one or more filters to the second half of the image, for example to clean up and isolate the image of the instance of the structured light pattern (e.g., laser line or stripe) in the second half of the image.

[0062] At 1326, each column of pixels is processed, for example successively column by column. For the respective column, the circuitry finds the centroid (e.g., peak, center along axis of column or thickness of line) of the structured light pattern (e.g., laser line) at 1328. For the respective column, the circuitry determines a range (z) and width distance across the belt (y) based on centroid location and column at 1330. For example, the circuitry may look up the corresponding range R and/or width W or calculate range R and/or width W.

[0063] At 1332, the circuitry averages the results from the processing of the first and the second halves of the image.

[0064] The method 1300 terminates at 1334, for example until invoked again. Alternatively, the method 1300 may repeat continually, for instance periodically. In some implementations, the method 1300 may be executed as a thread on a multi-threaded processor.

[0065] Various embodiments of the apparatus, devices and/or processes via the use of block diagrams, schematics, and examples have been set forth herein. Insofar as such block diagrams, schematics, and examples contain one or more functions and/or operations, it will be understood by those skilled in the art that each function and/or operation within such block diagrams, flowcharts, or examples can be implemented, individually and/or collectively, by a wide range of hardware, software, firmware, or virtually any combination thereof. In one embodiment, the present subject matter may be implemented via Application-Specific Integrated Circuits (ASICs). However, those skilled in the art will recognize that the embodiments disclosed herein, in whole or in part, can be equivalently implemented in standard integrated circuits, as one or more computer programs running on one or more computers (e.g., as one or more programs running on one or more computer systems), as one or more programs running on one or more controllers (e.g., micro-controllers), as one or more programs running on one or more processors (e.g., microprocessors), as firmware, or as virtually any combination thereof, and that designing the circuitry and/or writing the code for the software and/or firmware would be well within the skill of one of ordinary skill in the art in light of this disclosure.

[0066] When logic is implemented as software and stored in memory, one skilled in the art will appreciate that logic or information can be stored on any computer-readable medium for use by or in connection with any computer and/or processor related system or method. In the context of this document, a memory is a computer-readable medium that is an electronic, magnetic, optical, or other physical device or means that contains or stores a computer and/or processor program. Logic and/or the information can be embodied in any computer-readable medium for use by or in connection with an instruction execution system, apparatus, or device, such as a computer-based system, processor-containing system, or other system that can fetch the instructions from the instruction execution system, apparatus, or device and execute the instructions associated with logic and/or information. In the context of this specification, a "computer-readable medium" can be any means that can store, communicate, propagate, or transport the program associated with logic and/or information for use by or in connection with the instruction execution system, apparatus, and/or device. The computer-readable medium can be, for example, but is not limited to, an electronic, magnetic, optical, electromagnetic, infrared, or semiconductor system, apparatus, device, or propagation medium. More specific examples (a non-exhaustive list) of the computer-readable medium would include the following: an electrical connection having one or more wires, a portable computer diskette (magnetic, compact flash card, secure digital, or the like), a random access memory (RAM), a read-only memory (ROM), an erasable programmable read-only memory (EPROM, EEPROM, or Flash memory), an optical fiber, and a portable compact disc read-only memory (CDROM). Note that the computer-readable medium could even be paper or another suitable medium upon which the program associated with logic and/or information is printed, as the program can be electronically captured, via for instance optical scanning of the paper or other medium, then

compiled, interpreted or otherwise processed in a suitable manner if necessary, and then stored in memory.

[0067] In addition, those skilled in the art will appreciate that certain mechanisms taught herein are capable of being distributed as a program product in a variety of forms, and that an illustrative embodiment applies equally, regardless of the particular type of signal bearing media used to actually carry out the distribution. Examples of non-transitory signal bearing media include, but are not limited to, the following: recordable type media such as floppy disks, hard disk drives, CD ROMs, digital tape, and computer memory; and transitory or transmission type media such as digital and analog communication links using TDM or IP based communication links (e.g., packet links).

[0068] Those of skill in the art will recognize that many of the methods or algorithms set out herein may employ additional acts, may omit some acts, and/or may execute acts in a different order than specified. The various embodiments described above can be combined to provide further embodiments. Aspects of the embodiments can be modified, if necessary, to employ additional systems, circuits and concepts to provide yet further embodiments.

[0069] These and other changes can be made to the embodiments in light of the above-detailed description. In general, in the following claims, the terms used should not be construed to limit the claims to the specific embodiments disclosed in the specification and the claims, but should be construed to include all possible embodiments along with the full scope of equivalents to which such claims are entitled. Accordingly, the claims are not limited by the disclosure.

Claims

1. A system, comprising:

a light source (108) configured to generate a structured light pattern and operable to emit that structured light pattern outward into an environment;

a first reflective surface (112a) and a second reflective surface (112b), the first and the second reflective surfaces (112a, 112b) positioned with respect to the light source (108) to concurrently receive light returned from an object (104) in the environment as the structured light pattern (114), the second reflective surface (112b) oriented at a non-zero angle with respect to the first reflective surface (112a);

a light sensor (110) positioned to concurrently detect, in parallax, light reflected from the object (104) in the environment via both the first and the second reflective surfaces (112a, 112b), respectively as a first instance of the structured light pattern (114) reflected from the first reflective surface (112a) and a second instance of the structured light pattern (114) reflected from the second reflective surface (112b); and

at least one processor (134, 136, 138) communicatively coupled to the light sensor (110), and which is configured to correlate a relative position of the first and the second instances of the structured light pattern (114) detected by the light sensor (110) and is configured to determine at least one dimension related to the object (104) based at least in part on the correlation of the relative positions of the first and the second instances of the structured light pattern (114) detected by the light sensor (110);

characterized in that

the non-zero angle between the first and the second reflective surfaces (112a, 112b) is an obtuse angle that is less than 180 degrees.

2. The system of claims 1 wherein the first reflective surface (112a) is a planar surface that has a respective inner edge and the second reflective surface (112b) is a planar surface that has a respective inner edge, the second reflective surface (112b) spaced from the first reflective surface (112a) with a gap (250) between the respective inner edges of the first and the second reflective surfaces (112a, 112b), and the light passes through the gap (250) outward into the environment.

3. The system of any of the preceding claims wherein the light sensor (110) is a single two-dimensional light sensor (110), and further comprising:

at least one mirror positioned with respect to the light source (108) and operable to at least one of rotate or pivot to produce the structured light pattern (114).

4. The system of any of the preceding claims wherein the at least one dimension related to the object (104) determined by the at least one processor (134, 136, 138) includes at least one of a distance to a surface of the object (104), a height (H) of the object (104), a width (W) of the object (104) and a length (L) of the object (104).

5. The system of any of the preceding claims wherein to correlate a relative position of the first and the second instances of the structured light pattern (114) detected by the light sensor (110), the at least one processor (134, 136, 138):

for the first instance of the structured light pattern (114), determines at each of a plurality of positions along the first instance of the structured light pattern (114) a respective centroid for the first instance of the structured light pattern (114) at the respective position; and

for the second instance of the structured light pattern (114), determines at each of a plurality of positions along the second instance of the structured light pattern (114) a respective centroid for the second instance of the structured light pattern (114) at the respective position.

6. The system of claim 5 wherein to determine at least one dimension related to the object (104) based at least in part on the correlation of the relative positions of the first and the second instances of the structured light pattern (114), the at least one processor (134, 136, 138) determines a range (R) to the object (104) based on the determined centroids along the first and the second instances of the structured light pattern (114).

7. The system of claim 5 or 6 wherein the at least one processor (134, 136, 138) determines the range (R) to the object (104) based at least in part on the determined centroids for each of the positions along the first and the second instances of the structured light pattern (114) and further based on a set of calibration information.

8. The system of claims 6 or 7 wherein the at least one processor (134, 136, 138) averages the results of the determined range (R) to the object (104) based on the determined centroids for each of the positions along the first and the second instances of the structured light pattern (114).

9. The system of any of claims 6 - 8 wherein to determine at least one dimension related to the object (104) based at least in part on the correlation of the relative positions of the first and the second instances of the structured light pattern (114), the at least one processor (134, 136, 138) determines a height (H) of the object (104) based on the determined range (R) and a distance to a surface on which the object (104) is supported and/or determines a width (W) of the object (104) based on the determined centroids.

10. The system of any of claims 5 - 9 wherein the at least one processor (134, 136, 138) determines a width (W) of the object (104) based at least in part on the determined centroids for each of the positions along the first and the second instances of the structured light pattern (114).

11. The system of claim 10 wherein the at least one processor (134, 136, 138) averages the results of the determined width (W) of the object (104) based on the determined centroids for each of the positions along the first and the second instances of the structured light pattern (114).

12. The system of claims 10 or 11 wherein the at least one processor (134, 136, 138) determines the width (W) of the object (104) further based on a set of calibration information.

13. The system of any of the preceding claims wherein the light source (108) is a laser, the structured light is a linear pattern of laser light, and further comprising:
a lens and a bandpass filter in an optical path of the light sensor (110).

14. A method, comprising:

emitting a light beam by a light source (108);

reflecting light returned from an object (104) in an environment by a first reflective surface (112a);

concurrently reflecting the light returned from the object (104) in the environment by a second reflective surface (112b), the second reflective surface (112b) oriented at a non-zero angle with respect to the first reflective surface (112a);

detecting by a light sensor (110) the light reflected from the object (104) in the environment via both the first and the second reflective surfaces (112a, 112b) in parallax, respectively as a first instance of a structured light pattern (114) reflected from the first reflective surface (112a) and a second instance of the structured light pattern (114) reflected from the second reflective surface (112b); and

determining by at least one processor (134, 136, 138) communicatively coupled to the light sensor (110), at least one dimension related to the object (104) based at least in part on a correlation of a relative position of the first and the second instances of the structure light pattern detected by the light sensor (110);

characterized in that

the non-zero angle between the first and the second reflective surfaces (112a, 112b) is an obtuse angle that is less than 180 degrees, wherein the first reflective surface (112a) is a planar surface that has a respective inner

edge and the second reflective surface (112b) is a planar surface that has a respective inner edge, the second reflective surface (112b) spaced from the first reflective surface (112a) with a gap (250) between the respective inner edges of the first and the second reflective surfaces (112a, 112b), and the emitted light is directed such that it passes through the gap (250) outward into the environment.

Patentansprüche

1. System, umfassend:

eine Lichtquelle (108), die eingerichtet ist, um ein strukturiertes Lichtmuster zu erzeugen, und betriebsfähig ist, um das strukturierte Lichtmuster nach außen in eine Umgebung zu emittieren;
eine erste reflektierende Oberfläche (112a) und eine zweite reflektierende Oberfläche (112b), wobei die erste und die zweite reflektierende Oberfläche (112a, 112b) in Bezug auf die Lichtquelle (108) positioniert sind, um Licht gleichzeitig aufzunehmen, das von einem Objekt (104) in der Umgebung des strukturierten Lichtmusters (114) zurückgegeben wird, wobei die zweite reflektierende Oberfläche (112b) in Bezug auf die erste reflektierende Oberfläche (112a) in einem von Null verschiedenen Winkel ausgerichtet ist;
einen Lichtsensor (110), der positioniert ist, um gleichzeitig von dem Objekt (104) in der Umgebung über sowohl die erste als auch die zweite reflektierende Oberfläche (112a, 112b) reflektiertes Licht als eine erste Instanz des strukturierten Lichtmusters (114), das von der ersten reflektierenden Oberfläche (112a) reflektiert wird, bzw. als eine zweite Instanz des strukturierten Lichtmusters (114), das von der zweiten reflektierenden Oberfläche (112b) reflektiert wird, in Parallaxe zu erfassen; und
mindestens einen Prozessor (134, 136, 138), der kommunikativ mit dem Lichtsensor (110) gekoppelt und eingerichtet ist, um eine relative Position der ersten und der zweiten Instanz des strukturierten Lichtmusters (114), die durch den Lichtsensor (110) erfasst wurden, zu korrelieren, und eingerichtet ist, um zumindest teilweise auf der Grundlage der Korrelation der relativen Positionen der ersten und der zweiten Instanz des durch den Lichtsensor (110) erfassten strukturierten Lichtmusters (114) mindestens eine Abmessung in Bezug auf das Objekt (104) zu ermitteln;
dadurch gekennzeichnet, dass
der von Null verschiedene Winkel zwischen der ersten und der zweiten reflektierenden Oberfläche (112a, 112b) ein stumpfer Winkel von weniger als 180 Grad ist.

2. System nach Anspruch 1 wobei die erste reflektierende Oberfläche (112a) eine ebene Oberfläche ist, die eine entsprechende Innenkante aufweist, und die zweite reflektierende Oberfläche (112b) eine ebene Oberfläche ist, die eine entsprechende Innenkante aufweist, wobei die zweite reflektierende Oberfläche (112b) in einem Abstand von der ersten reflektierenden Oberfläche (112a) mit einem Spalt (250) zwischen den jeweiligen Innenkanten der ersten und der zweiten reflektierenden Oberfläche (112a, 112b) angeordnet ist und das Licht durch den Spalt (250) nach außen in die Umgebung gelangt.

3. System nach einem der vorstehenden Ansprüche, wobei der Lichtsensor (110) ein einzelner zweidimensionaler Lichtsensor (110) ist und ferner umfasst:
mindestens einen Spiegel, der in Bezug auf die Lichtquelle (108) positioniert und betriebsfähig ist, um sich mindestens zu drehen oder zu schwenken, um das strukturierte Lichtmuster (114) zu erzeugen.

4. System nach einem der vorstehenden Ansprüche, wobei die durch den mindestens einen Prozessor (134, 136, 138) in Bezug auf das Objekt (104) ermittelte mindestens eine Abmessung mindestens eines einschließt von einem Abstand zu einer Oberfläche des Objekts (104), einer Höhe (H) des Objekts (104), einer Breite (W) des Objekts (104) und einer Länge (L) des Objekts (104).

5. System nach einem der vorstehenden Ansprüche, wobei zur Korrelation einer relativen Position der ersten und der zweiten Instanz des strukturierten Lichtmusters (114), die durch den Lichtsensor (110) erfasst wurden, der mindestens eine Prozessor (134, 136, 138):

für die erste Instanz des strukturierten Lichtmusters (114) bei jeder von einer Vielzahl von Positionen entlang der ersten Instanz des strukturierten Lichtmusters (114) einen jeweiligen geometrischen Schwerpunkt für die erste Instanz des strukturierten Lichtmusters (114) an der jeweiligen Position ermittelt; und
für die zweite Instanz des strukturierten Lichtmusters (114) bei jeder von einer Vielzahl von Positionen entlang der zweiten Instanz des strukturierten Lichtmusters (114) einen jeweiligen geometrischen Schwerpunkt für die

zweite Instanz des strukturierten Lichtmusters (114) an der jeweiligen Position ermittelt.

- 5 6. System nach Anspruch 5, wobei zur Ermittlung mindestens einer Abmessung in Bezug auf das Objekt (104) zumindest teilweise auf der Grundlage der Korrelation der relativen Positionen der ersten und der zweiten Instanz des strukturierten Lichtmusters (114) der mindestens eine Prozessor (134, 136, 138) einen Bereich (R) zu dem Objekt (104) auf der Grundlage der ermittelten geometrischen Schwerpunkte entlang der ersten und der zweiten Instanz des strukturierten Lichtmusters (114) ermittelt.
- 10 7. System nach Anspruch 5 oder 6 wobei der mindestens eine Prozessor (134, 136, 138) den Bereich (R) zu dem Objekt (104) zumindest teilweise auf der Grundlage der ermittelten geometrischen Schwerpunkte für jede der Positionen entlang der ersten und der zweiten Instanz des strukturierten Lichtmusters (114) und ferner auf der Grundlage eines Satzes von Kalibrierungsinformationen ermittelt.
- 15 8. System nach Anspruch 6 oder 7 wobei der mindestens eine Prozessor (134, 136, 138) die Ergebnisse des ermittelten Bereichs (R) zu dem Objekt (104) auf der Grundlage der für jede der Positionen entlang der ersten und der zweiten Instanz des strukturierten Lichtmusters (114) ermittelten geometrischen Schwerpunkte ermittelt.
- 20 9. Verfahren nach einem der Ansprüche 6-8, wobei zur Ermittlung mindestens einer Abmessung in Bezug auf das Objekt (104) zumindest teilweise auf der Grundlage der Korrelation der relativen Positionen der ersten und der zweiten Instanz des strukturierten Lichtmusters (114) der mindestens eine Prozessor (134, 136, 138) eine Höhe (H) des Objekts (104) auf der Grundlage des ermittelten Bereichs (R) und eines Abstands zu einer Oberfläche ermittelt, auf der das Objekt (104) abgestützt ist, und/oder eine Breite (W) des Objekts (104) auf der Grundlage der ermittelten geometrischen Schwerpunkte ermittelt.
- 25 10. System nach einem der Ansprüche 5-9, wobei der mindestens eine Prozessor (134, 136, 138) eine Breite (W) des Objekts (104) zumindest teilweise auf der Grundlage der für jede der Positionen entlang der ersten und der zweiten Instanz des strukturierten Lichtmusters (114) ermittelten geometrischen Schwerpunkte ermittelt.
- 30 11. System nach Anspruch 10 wobei der mindestens eine Prozessor (134, 136, 138) die Ergebnisse der ermittelten Breite (W) des Objekts (104) auf der Grundlage der für jede der Positionen entlang der ersten und der zweiten Instanz des strukturierten Lichtmusters (114) ermittelten geometrischen Schwerpunkte ermittelt.
- 35 12. System nach Anspruch 10 oder 11, wobei der mindestens eine Prozessor (134, 136, 138) die Breite (W) des Objekts (104) ferner auf der Grundlage eines Satzes von Kalibrierungsinformationen ermittelt.
- 40 13. System nach einem der vorstehenden Ansprüche, wobei die Lichtquelle (108) ein Laser ist, das strukturierte Licht ein lineares Muster von Laserlicht ist und ferner umfassend:
eine Linse und ein Bandpassfilter in einem Strahlenweg des Lichtsensors (110).
- 45 14. Verfahren, umfassend:
Emittieren eines Lichtstrahls durch eine Lichtquelle (108);
Reflektieren von Licht, das von einem Objekt (104) in einer Umgebung durch eine erste reflektierende Oberfläche (112a) zurückgegeben wird;
gleichzeitiges Reflektieren des von dem Objekt (104) in der Umgebung zurückgegebenen Lichts durch eine
zweite reflektierende Oberfläche (112b), wobei die zweite reflektierende Oberfläche (112b) in Bezug auf die
erste reflektierende Oberfläche (112a) in einem von Null verschiedenen Winkel ausgerichtet ist;
durch einen Lichtsensor (110) Erfassen in Parallaxe des von dem Objekt (104) in der Umgebung über sowohl
die erste als auch die zweite reflektierende Oberfläche (112a, 112b) reflektierten Lichts als eine erste Instanz
des strukturierten Lichtmusters (114), das von der ersten reflektierenden Oberfläche (112a) reflektiert wird,
bzw. als eine zweite Instanz des strukturierten Lichtmusters (114), das von der zweiten reflektierenden Oberfläche (112b) reflektiert wird; und
durch den kommunikativ mit dem Lichtsensor (110) gekoppelten, mindestens einen Prozessor (134, 136, 138)
Ermitteln mindestens einer Abmessung in Bezug auf das Objekt (104) zumindest teilweise auf der Grundlage
einer Korrelation der relativen Position der ersten und der zweiten Instanz des durch den Lichtsensor (110)
erfassten Strukturlichtmusters;
dadurch gekennzeichnet, dass
der von null verschiedene Winkel zwischen der ersten und der zweiten reflektierenden Oberfläche (112a, 112b)

ein stumpfer Winkel ist, der weniger als 180 Grad beträgt, wobei die erste reflektierende Oberfläche (112a) eine ebene Oberfläche ist, die eine entsprechende Innenkante aufweist, und die zweite reflektierende Oberfläche (112b) eine ebene Oberfläche ist, die eine entsprechende Innenkante aufweist, wobei die zweite reflektierende Oberfläche (112b) in einem Abstand von der ersten reflektierenden Oberfläche (112a) mit einem Spalt (250) zwischen den jeweiligen Innenkanten der ersten und der zweiten reflektierenden Oberfläche (112a, 112b) angeordnet ist und das emittierte Licht so gerichtet ist, dass es durch den Spalt (250) nach außen in die Umgebung gelangt.

Revendications

1. Système, comprenant :

une source de lumière (108) configurée pour générer un motif lumineux structuré et opérationnelle pour émettre ce motif lumineux structuré vers l'extérieur dans un environnement ;

une première surface réfléchissante (112a) et une deuxième surface réfléchissante (112b), les première et deuxième surfaces réfléchissantes (112a, 112b) positionnées par rapport à la source de lumière (108) pour recevoir simultanément de la lumière renvoyée d'un objet (104) dans l'environnement en guise de motif lumineux structuré (114), la deuxième surface réfléchissante (112b) orientée selon un angle différent de zéro par rapport à la première surface réfléchissante (112a) ;

un capteur de lumière (110) positionné pour détecter simultanément, en parallaxe, de la lumière réfléchi par l'objet (104) dans l'environnement via à la fois les première et deuxième surfaces réfléchissantes (112a, 112b), respectivement en tant que première instance du motif lumineux structuré (114) réfléchi par la première surface réfléchissante (112a) et deuxième instance du motif lumineux structuré (114) réfléchi par la deuxième surface réfléchissante (112b) ; et

au moins un processeur (134, 136, 138) couplé par communications avec le capteur de lumière (110), et qui est configuré pour corrélérer une position relative des première et deuxième instances du motif lumineux structuré (114) détectées par le capteur de lumière (110) et est configuré pour déterminer au moins une dimension se rapportant à l'objet (104) sur la base au moins en partie de la corrélation des positions relatives des première et deuxième instances du motif lumineux structuré (114) détectées par le capteur de lumière (110) ;

caractérisé en ce que

l'angle différent de zéro entre les première et deuxième surfaces réfléchissantes (112a, 112b) est un angle obtus qui est inférieur à 180 degrés.

2. Système selon la revendication 1, dans lequel la première surface réfléchissante (112a) est une surface plane qui a un bord interne respectif et la deuxième surface réfléchissante (112b) est une surface plane qui a un bord interne respectif, la deuxième surface réfléchissante (112b) espacée de la première surface réfléchissante (112a) avec un espace (250) entre les bords internes respectifs des première et deuxième surfaces réfléchissantes (112a, 112b), et la lumière passe à travers l'espace (250) vers l'extérieur dans l'environnement.

3. Système selon l'une quelconque des revendications précédentes dans lequel le capteur de lumière (110) est un unique capteur de lumière bidimensionnel (110), et comprenant en outre :
au moins un miroir positionné par rapport à la source de lumière (108) et opérationnel pour au moins l'un parmi une rotation ou un pivotement pour produire le motif lumineux structuré (114).

4. Système selon l'une quelconque des revendications précédentes dans lequel l'au moins une dimension se rapportant à l'objet (104) déterminée par l'au moins un processeur (134, 136, 138) inclut au moins l'une parmi une distance jusqu'à une surface de l'objet (104), une hauteur (H) de l'objet (104), une largeur (W) de l'objet (104) et une longueur (L) de l'objet (104).

5. Système selon l'une quelconque des revendications précédentes dans lequel pour corrélérer une position relative des première et deuxième instances du motif lumineux structuré (114) détectées par le capteur de lumière (110), l'au moins un processeur (134, 136, 138) :

pour la première instance du motif lumineux structuré (114), détermine à chacune d'une pluralité de positions le long de la première instance du motif lumineux structuré (114) un centroïde respectif pour la première instance du motif lumineux structuré (114) à la position respective ; et
pour la deuxième instance du motif lumineux structuré (114), détermine à chacune d'une pluralité de positions

le long de la deuxième instance du motif lumineux structuré (114) un centroïde respectif pour la deuxième instance du motif lumineux structuré (114) à la position respective.

- 5 6. Système selon la revendication 5 dans lequel pour déterminer au moins une dimension se rapportant à l'objet (104) sur la base au moins en partie de la corrélation des positions relatives des première et deuxième instances du motif lumineux structuré (114), l'au moins un processeur (134, 136, 138) détermine une étendue (R) jusqu'à l'objet (104) sur la base des centroïdes déterminés le long des première et deuxième instances du motif lumineux structuré (114).
- 10 7. Système selon la revendication 5 ou 6 dans lequel l'au moins un processeur (134, 136, 138) détermine l'étendue (R) jusqu'à l'objet (104) sur la base au moins en partie des centroïdes déterminés pour chacune des positions le long des première et deuxième instances du motif lumineux structuré (114) et sur la base en outre d'un ensemble d'informations d'étalonnage.
- 15 8. Système selon les revendications 6 ou 7 dans lequel l'au moins un processeur (134, 136, 138) établit la moyenne des résultats de l'étendue déterminée (R) jusqu'à l'objet (104) sur la base des centroïdes déterminés pour chacune des positions le long des première et deuxième instances du motif lumineux structuré (114).
- 20 9. Système selon l'une quelconque des revendications 6 à 8 dans lequel pour déterminer au moins une dimension se rapportant à l'objet (104) sur la base au moins en partie de la corrélation des positions relatives des première et deuxième instances du motif lumineux structuré (114), l'au moins un processeur (134, 136, 138) détermine une hauteur (H) de l'objet (104) sur la base de l'étendue déterminée (R) et de la distance jusqu'à une surface sur laquelle l'objet (104) est supporté et/ou détermine une largeur (W) de l'objet (104) sur la base des centroïdes déterminés.
- 25 10. Système selon l'une quelconque des revendications 5 à 9 dans lequel l'au moins un processeur (134, 136, 138) détermine une largeur (W) de l'objet (104) sur la base au moins en partie des centroïdes déterminés pour chacune des positions le long des première et deuxième instances du motif lumineux structuré (114).
- 30 11. Système selon la revendication 10 dans lequel l'au moins un processeur (134, 136, 138) établit la moyenne des résultats de la largeur déterminée (W) de l'objet (104) sur la base des centroïdes déterminés pour chacune des positions le long des première et deuxième instances du motif lumineux structuré (114).
- 35 12. Système selon les revendications 10 ou 11 dans lequel l'au moins un processeur (134, 136, 138) détermine la largeur (W) de l'objet (104) sur la base en outre d'un ensemble d'informations d'étalonnage.
- 40 13. Système selon l'une quelconque des revendications précédentes dans lequel la source de lumière (108) est un laser, la lumière structurée est un motif linéaire de lumière laser, et comprenant en outre :
une lentille et un filtre passe-bande dans un trajet optique du capteur de lumière (110).
- 45 14. Procédé, comprenant :
l'émission d'un faisceau de lumière par une source de lumière (108) ;
la réflexion de lumière renvoyée d'un objet (104) dans un environnement par une première surface réfléchissante (112a) ;
la réflexion simultanée de la lumière renvoyée par l'objet (104) dans l'environnement par une deuxième surface réfléchissante (112b), la deuxième surface réfléchissante (112b) orientée selon un angle différent de zéro par rapport à la première surface réfléchissante (112a) ;
la détection par un capteur de lumière (110) de la lumière réfléchi par l'objet (104) dans l'environnement via à la fois les première et deuxième surfaces réfléchissantes (112a, 112b) en parallaxe, respectivement en tant que première instance d'un motif lumineux structuré (114) réfléchi par la première surface réfléchissante (112a) et deuxième instance du motif lumineux structuré (114) réfléchi par la deuxième surface réfléchissante (112b) ;
et la détermination par au moins un processeur (134, 136, 138) couplé par communications avec le capteur de lumière (110), d'au moins une dimension se rapportant à l'objet (104) sur la base au moins en partie d'une corrélation d'une position relative des première et deuxième instances du motif lumineux structuré détecté par le capteur de lumière (110) ;
55 **caractérisé en ce que**
l'angle différent de zéro entre les première et deuxième surfaces réfléchissantes (112a, 112b) est un angle obtus qui est inférieur à 180 degrés, dans lequel la première surface réfléchissante (112a) est une surface plane qui a un bord interne respectif et la deuxième surface réfléchissante (112b) est une surface plane qui a

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un bord interne respectif, la deuxième surface réfléchissante (112b) espacée de la première surface réfléchissante (112a) avec un espace (250) entre les bords internes respectifs des première et deuxième surfaces réfléchissantes (112a, 112b), et la lumière émise est dirigée de telle sorte qu'elle passe à travers l'espace (250) vers l'extérieur dans l'environnement.

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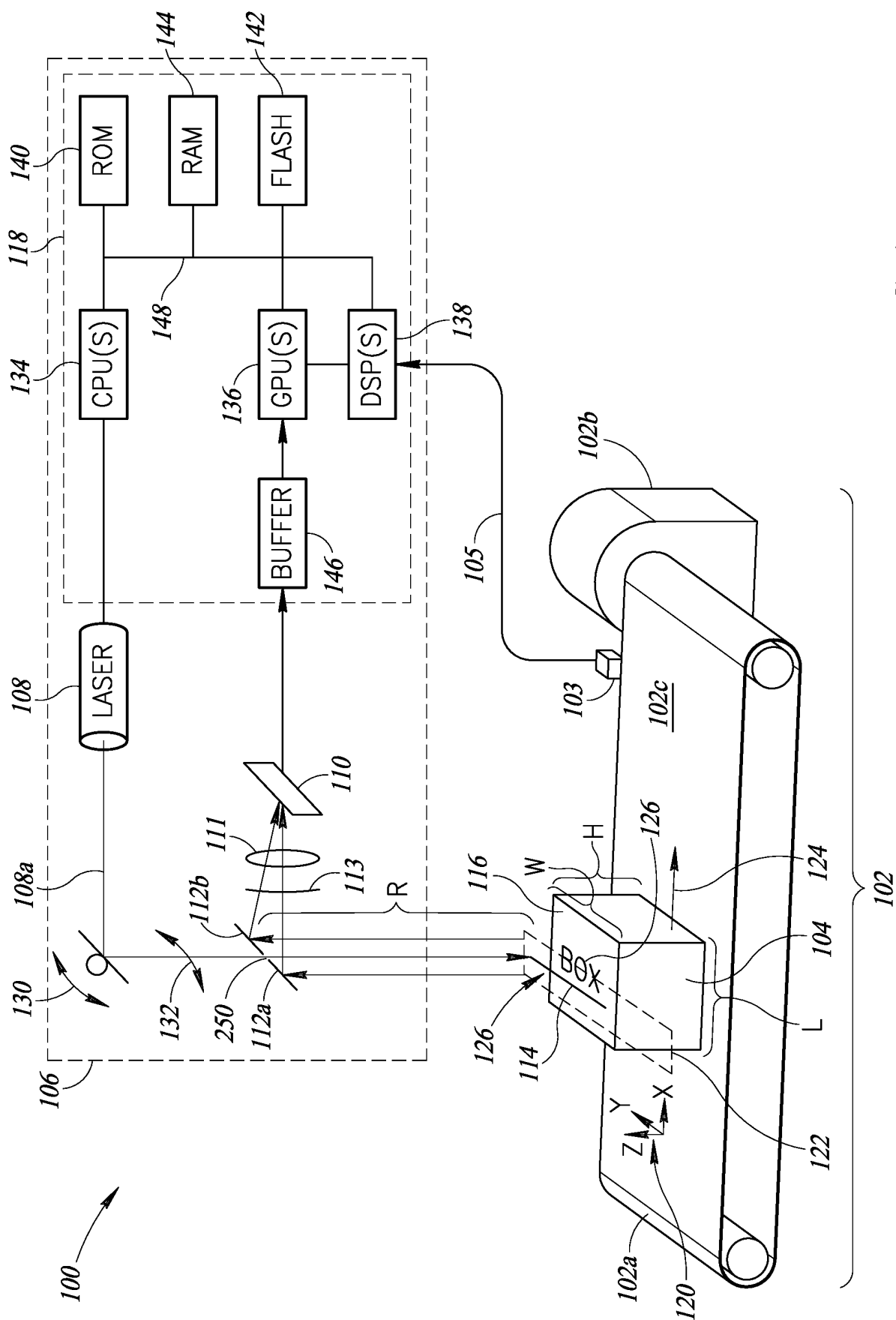


FIG. 1

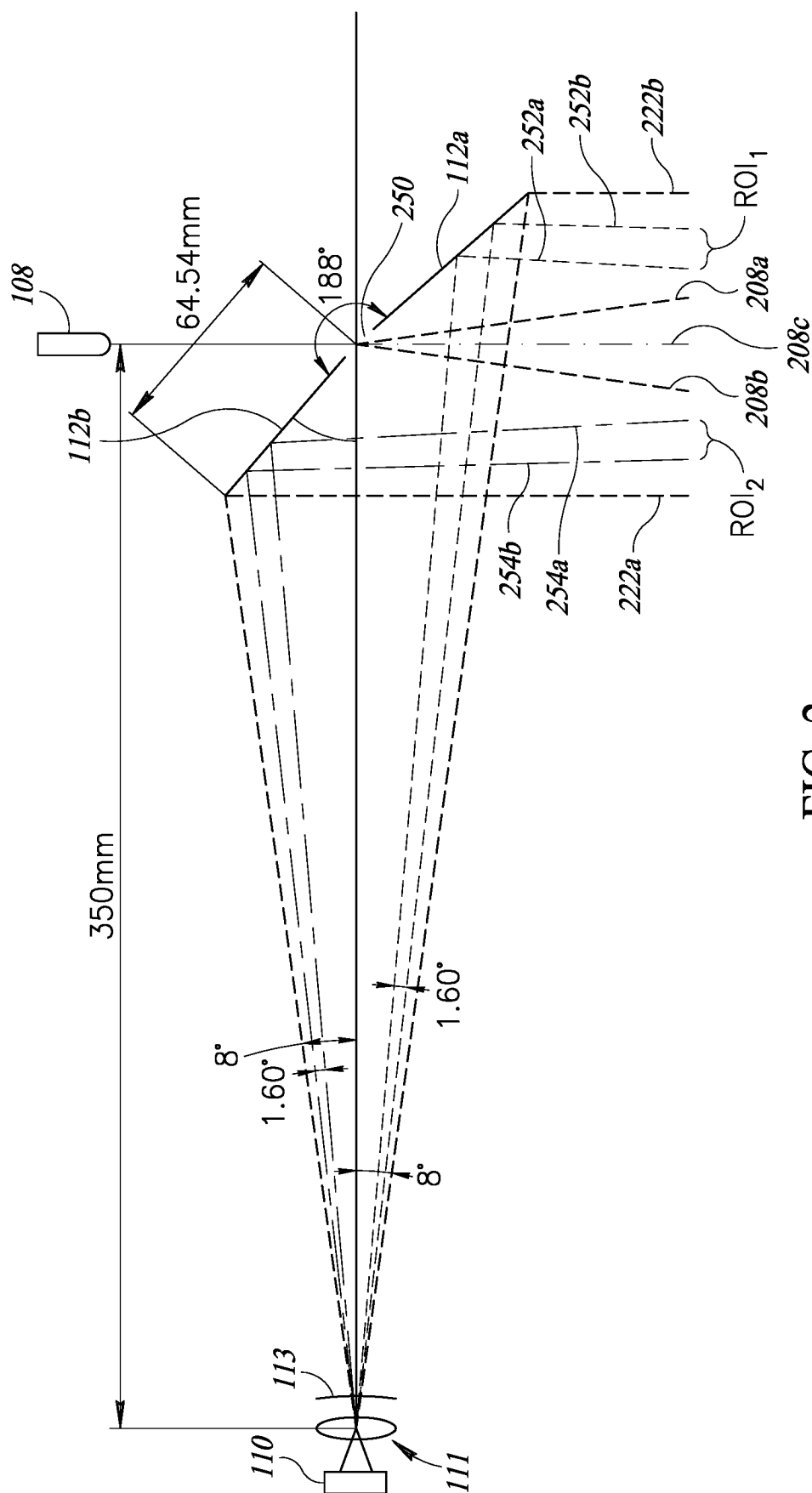


FIG. 2

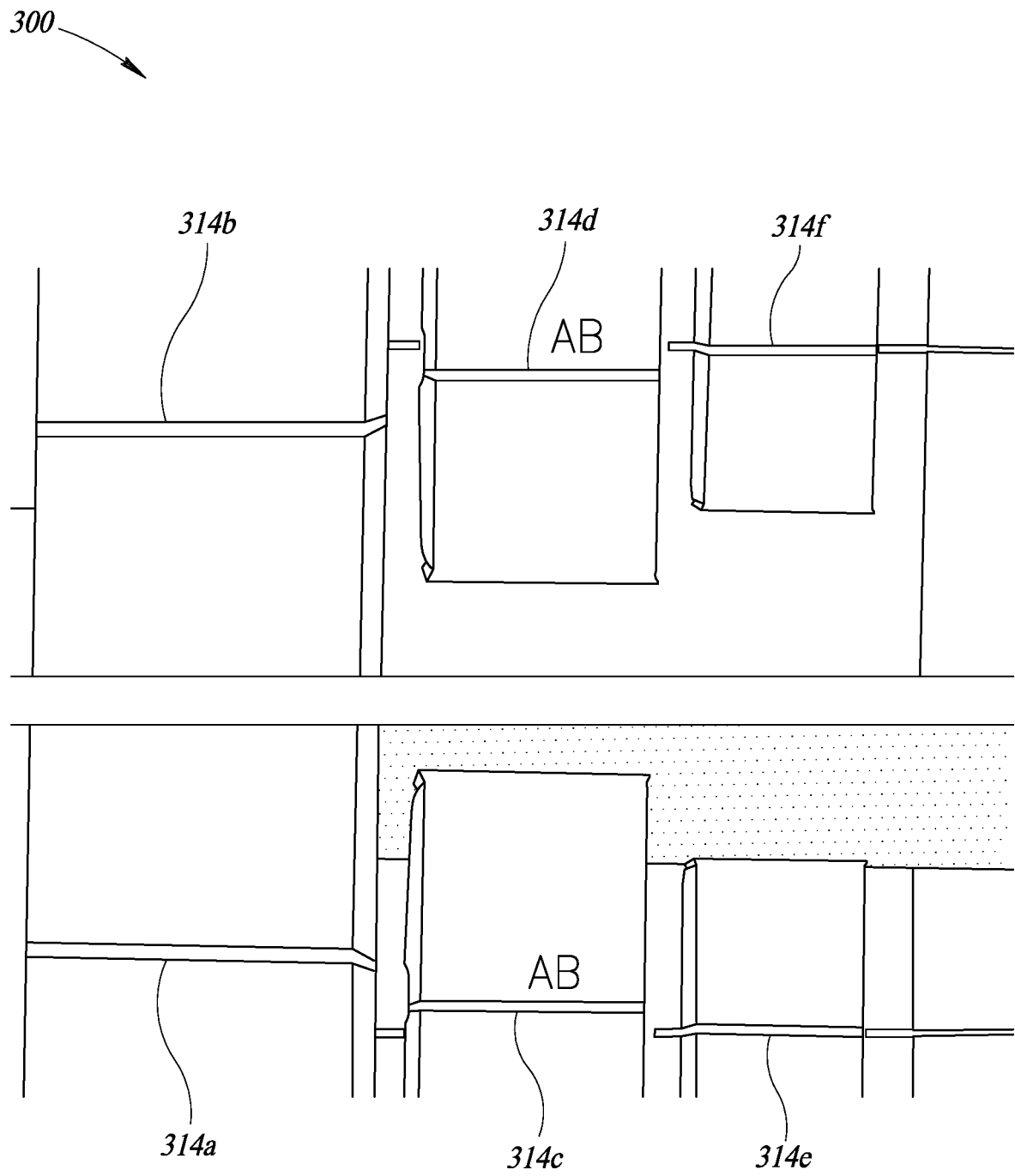


FIG. 3

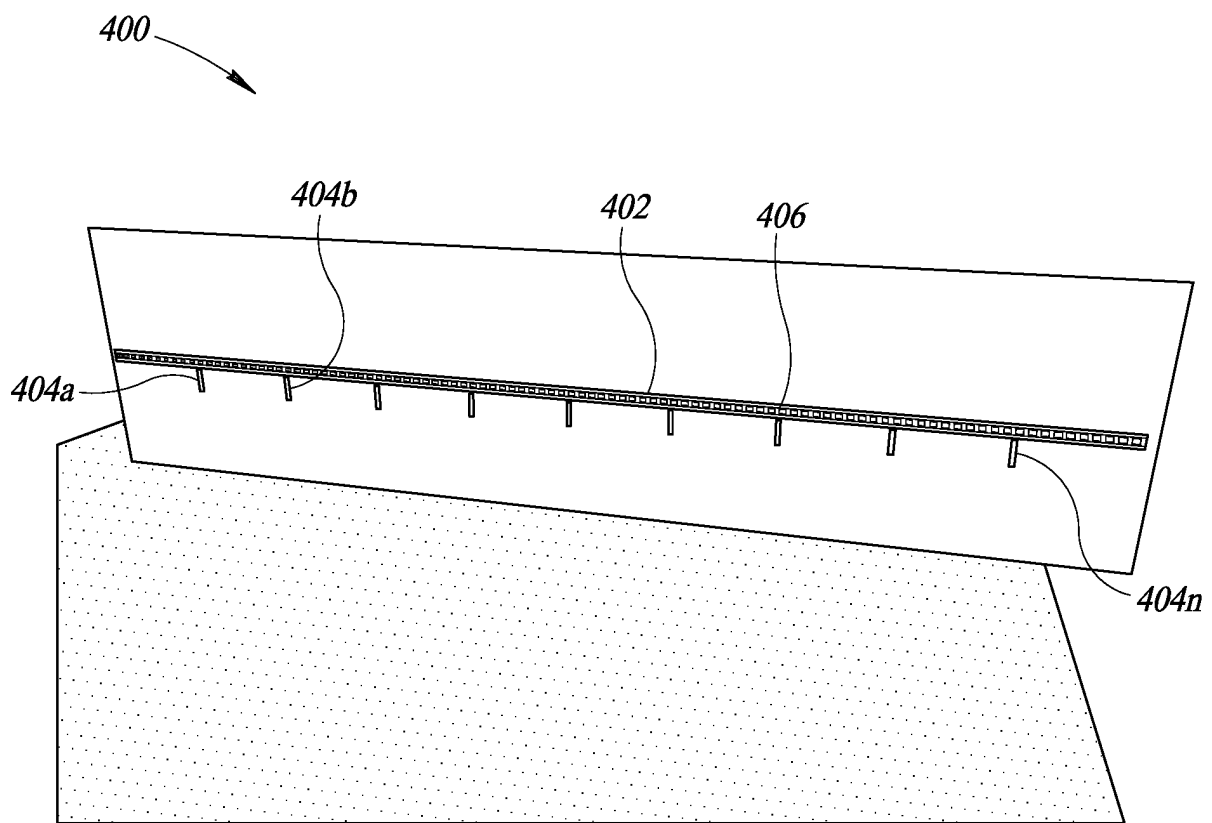


FIG. 4

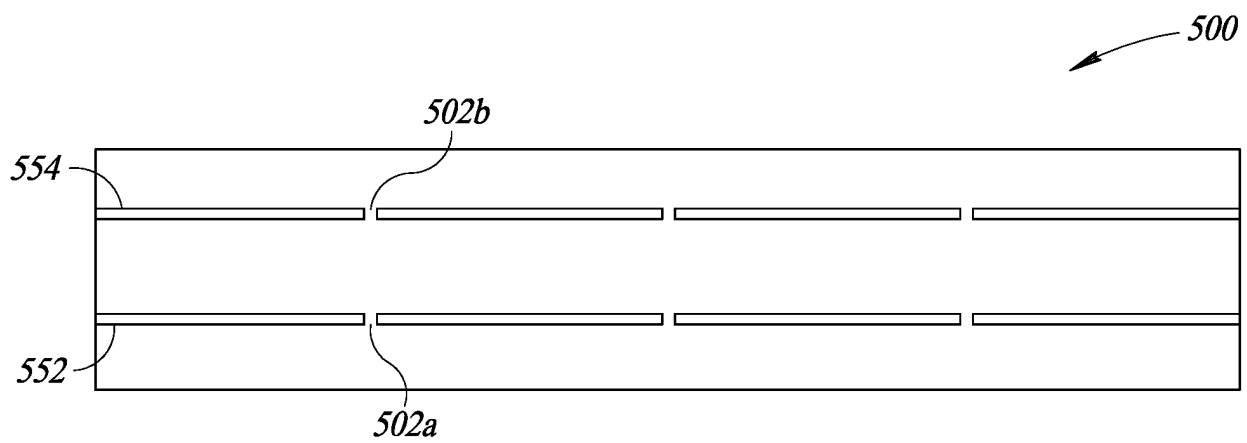


FIG. 5

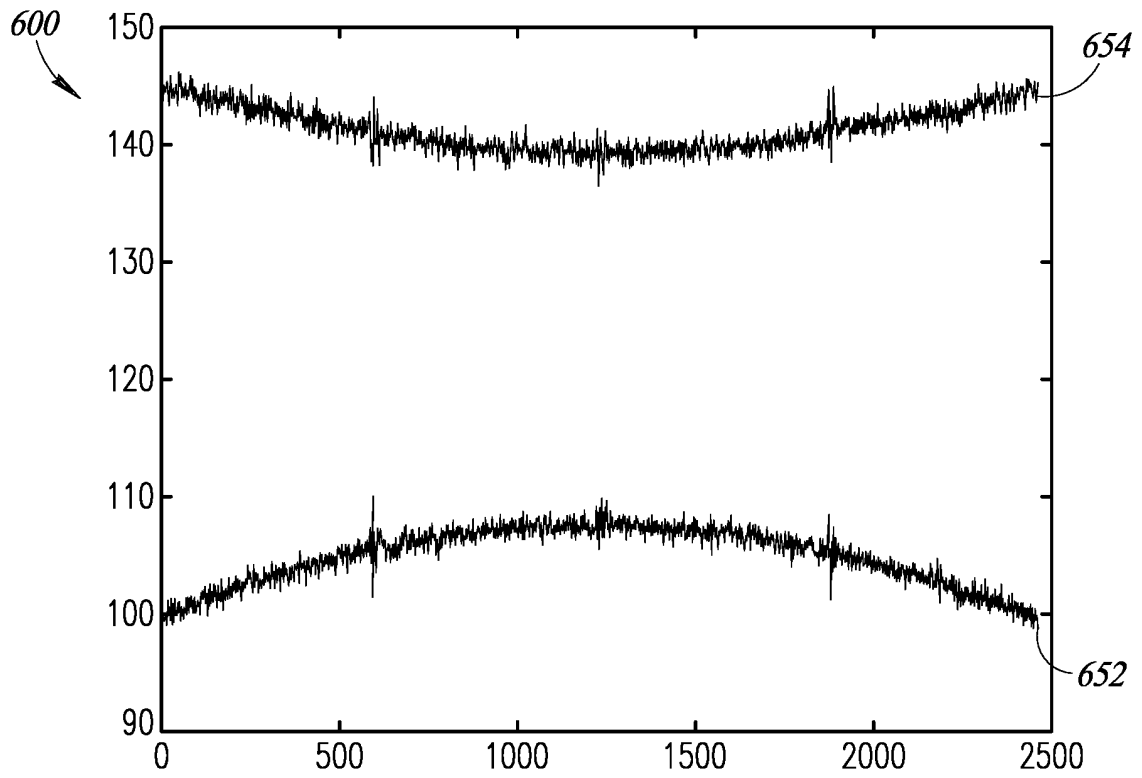


FIG. 6

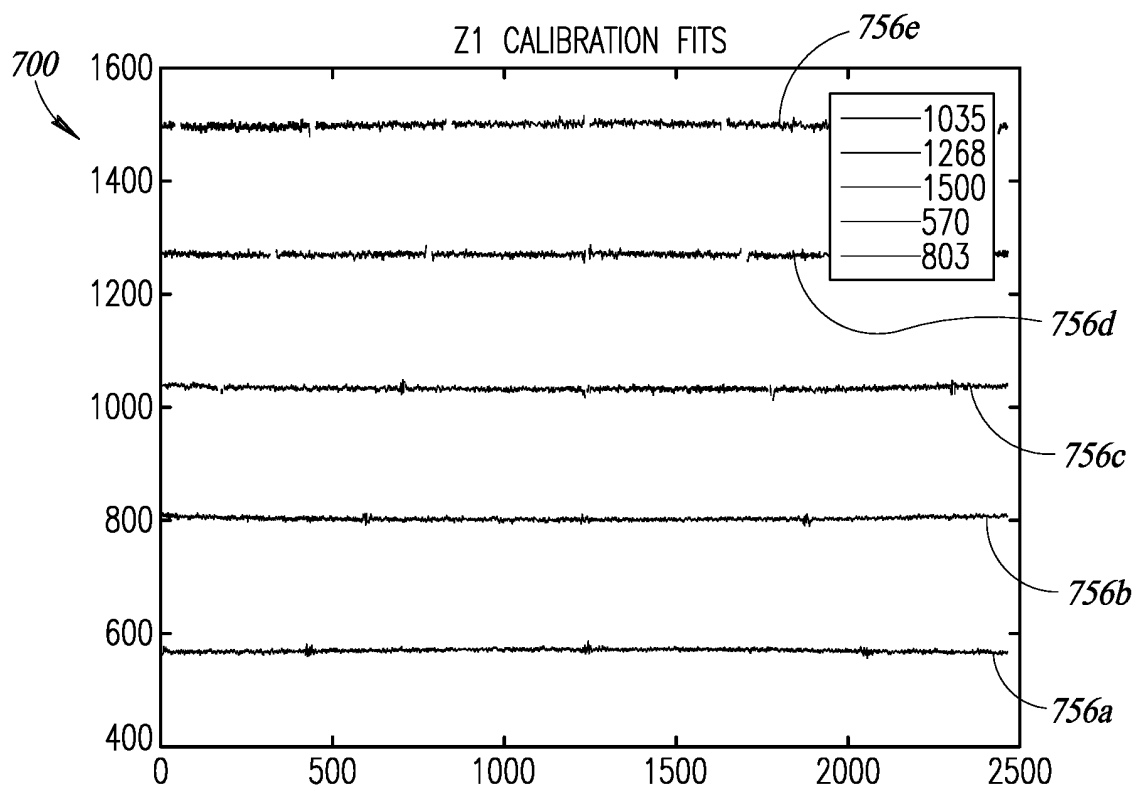


FIG. 7

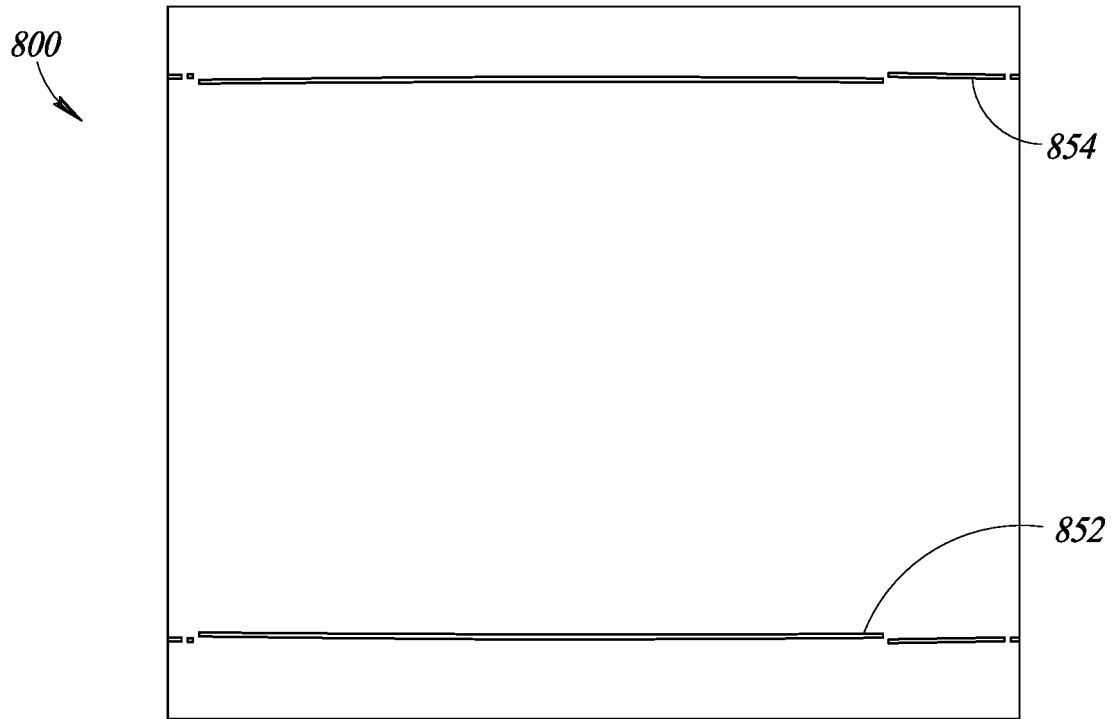


FIG. 8

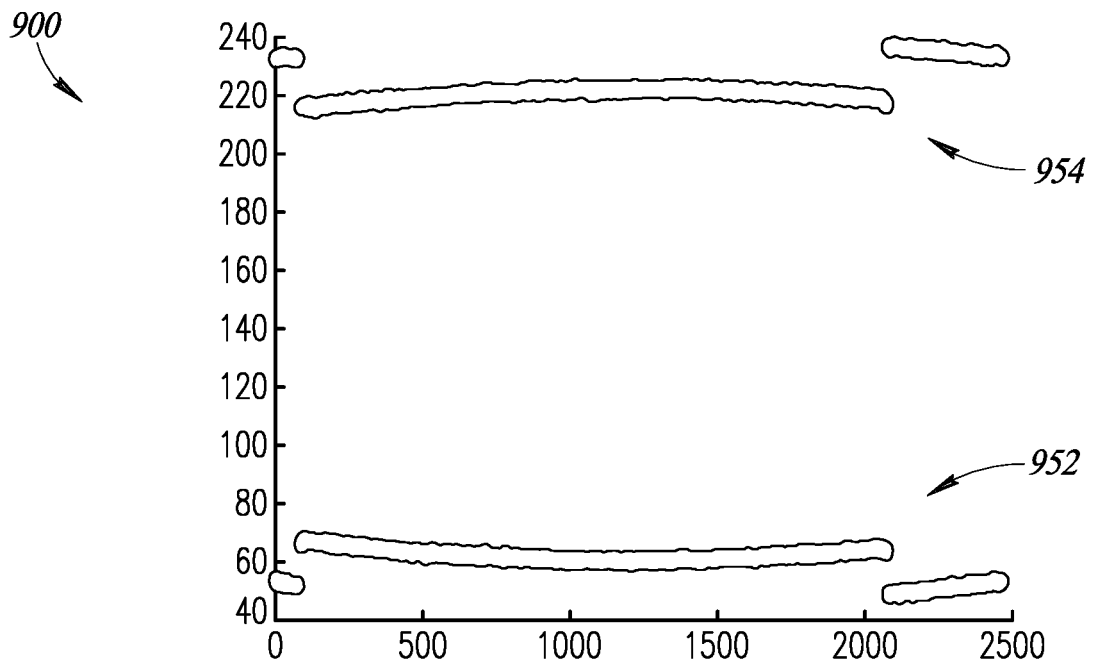


FIG. 9

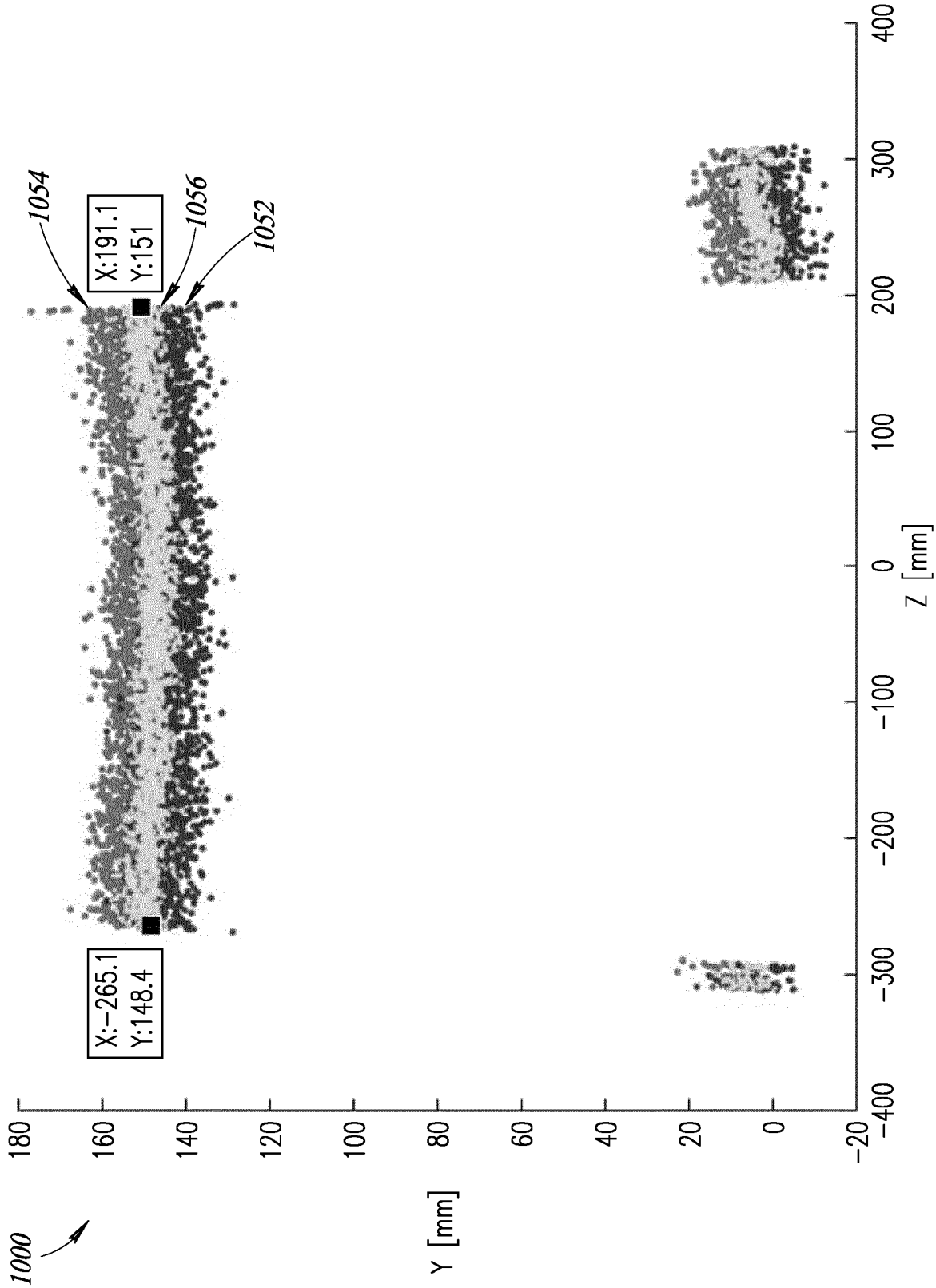


FIG. 10

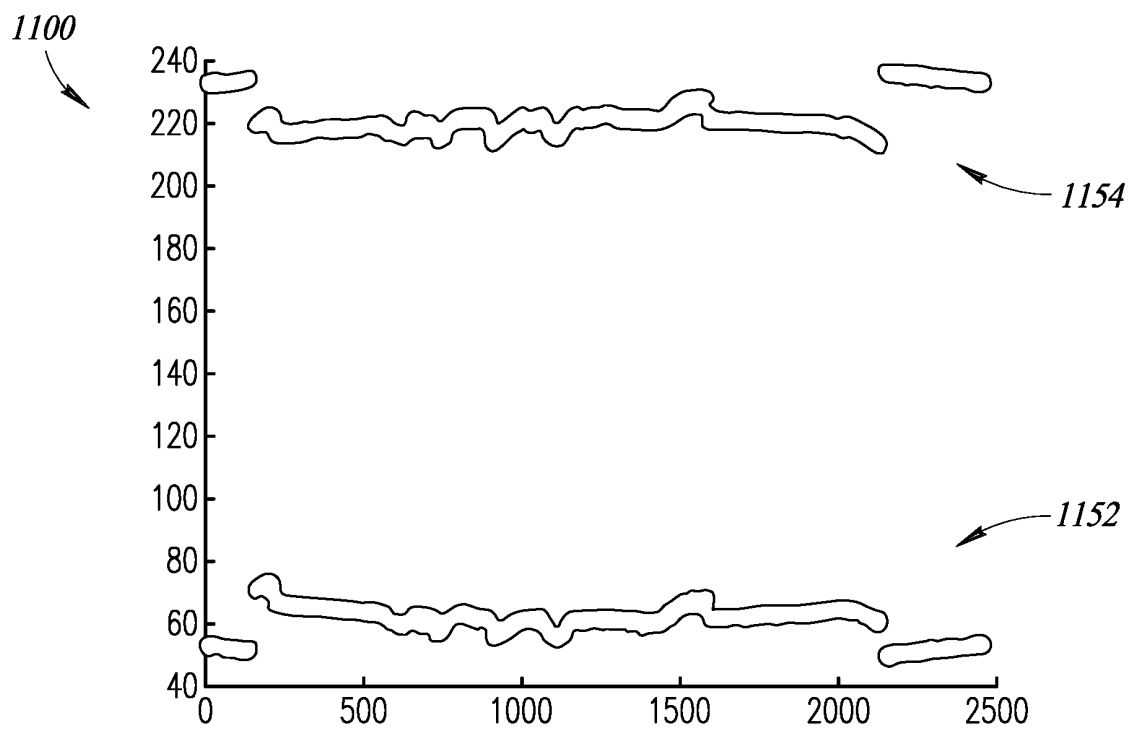


FIG. 11

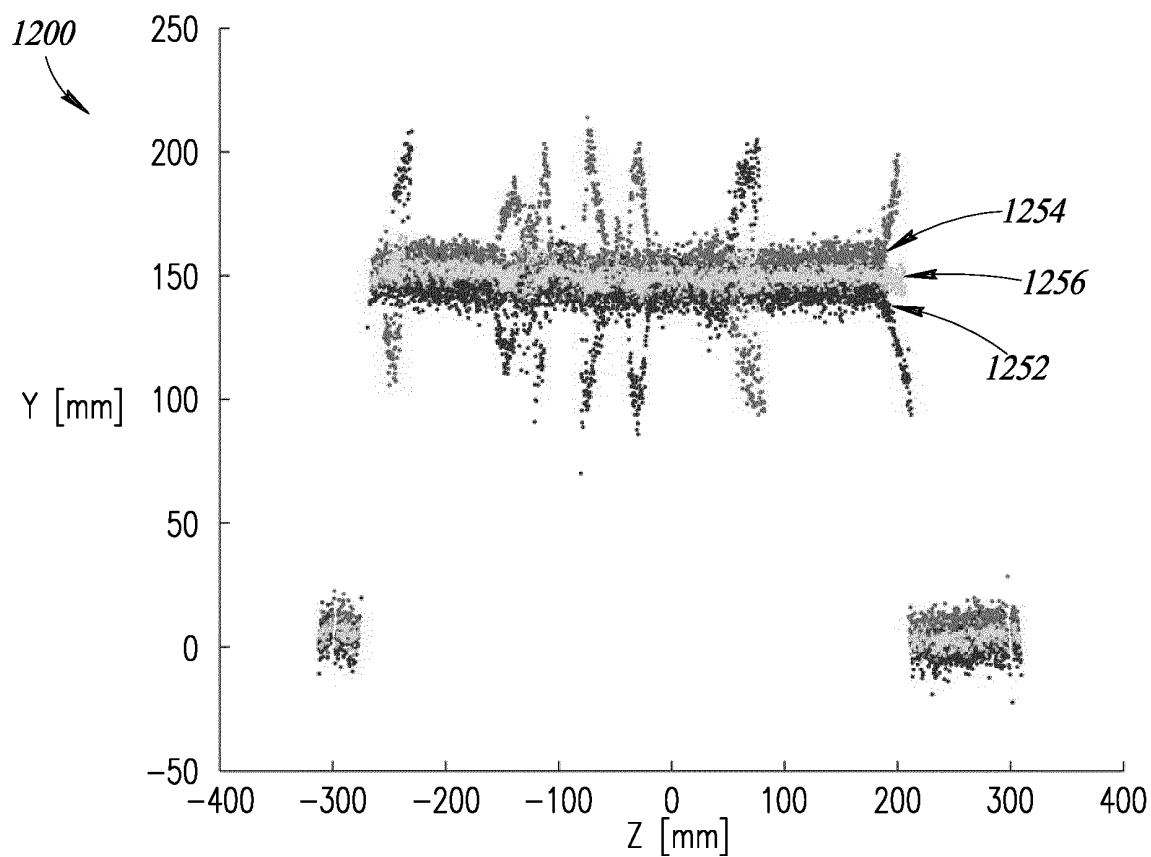


FIG. 12

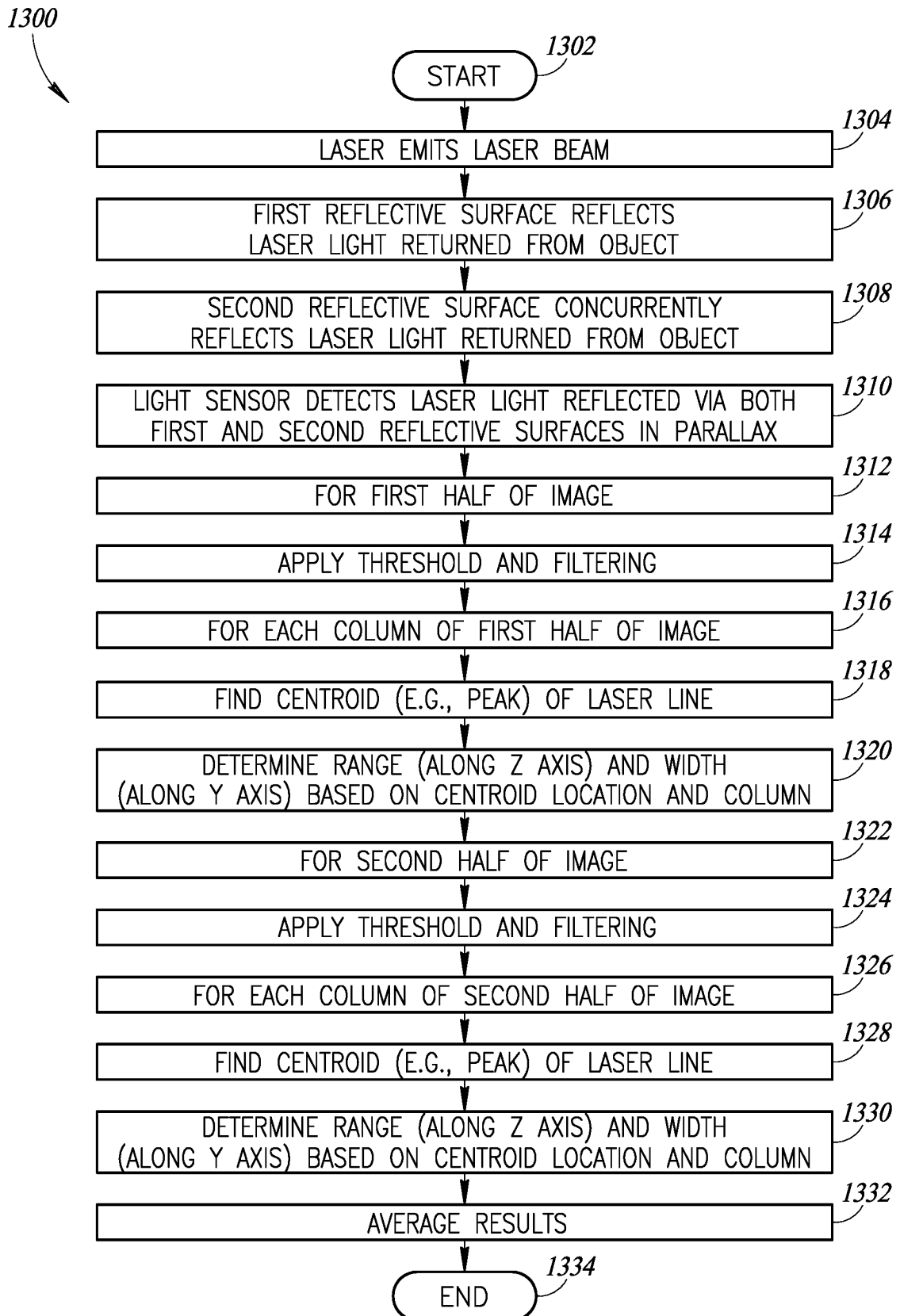


FIG. 13

REFERENCES CITED IN THE DESCRIPTION

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